

Notice of References Cited

Application/Control No.

09/735,840

Applicant(s)/Patent Under
Reexamination
NOZAKI, TAKEO

Examiner

Ryan J Hesseltine

Art Unit

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| | A | US-4,559,603 | 12-1985 | Yoshikawa, Ryoichi | 716/5 |
| | B | US-4,846,577 | 07-1989 | Grindon, John R. | 356/610 |
| | C | US-4,962,541 | 10-1990 | Doi et al. | 382/144 |
| | D | US-5,016,191 | 05-1991 | Radochonski, Pierre A. | 345/596 |
| | E | US-6,040,911 A | 03-2000 | Nozaki et al. | 356/394 |
| | F | US-6,076,465 A | 06-2000 | Vacca et al. | 101/481 |
| | G | US-6,356,300 B1 | 03-2002 | Shiba, Hisashi | 348/130 |
| | H | US-6,504,947 B1 | 01-2003 | Nozaki et al. | 382/148 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Li et al. "Subpixel edge detection and estimation with a microprocessor-controlled line scan camera." IEEE Transactions on Industrial Electronics, Vol. 35, No. 1, Feb. 1998, pp. 105-112. |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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